

Wavelet Applications in Industrial Processing VI

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Contents

v Conference Committee

SESSION 1 THE JPEG 2000 FAMILY OF STANDARDS

7248 02 **The JPEG 2000 family of standards (Invited Paper)** [7248-01] P. Schelkens, T. Bruylants, F. Temmermans, J. Barbarien, A. Dooms, A. Munteanu, Vrije Univ. Brussel (Belgium)

SESSION 2 TOOLS FOR SIGNAL AND IMAGE ANALYSIS

- 7248 03 **Multiridgelets for texture analysis** [7248-02] H.-J. Yoon, C.-C. Li, Univ. of Pittsburgh (United States)
- 7248 04 **Kolmogorov superposition theorem and its application to wavelet image decompositions** [7248-03] P.-E. Leni, Y. D. Fougerolle, F. Truchetet, Lab. LE2I, CNRS, Univ. de Bourgogne (France)

SESSION 3 COMPRESSION

SESSION 4	PHYSICS-BASED MODELS AND APPLICATIONS I
7248 0A	Estimation of interband and intraband statistical dependencies in wavelet-based decomposition of meshes [7248-10] S. M. Satti, L. Denis, A. Munteanu, J. Cornelis, P. Schelkens, Vrije Univ. Brussel (Belgium)
7248 09	Locally adaptive passive error concealment for wavelet coded video [7248-09] J. Rombaut, A. Pižurica, W. Philips, Ghent Univ. (Belgium)
7248 08	A novel efficient image compression system based on independent component analysis [7248-07] Z. Shahid, F. Dupont, A. Baskurt, LIRIS, CNRS, Univ. de Lyon (France)
7248 07	Semi-regular 3D mesh progressive compression and transmission based on an adaptive wavelet decomposition [7248-06] C. Roudet, F. Dupont, CNRS, Univ. de Lyon (France) and LIRIS, Univ. Lyon 1 (France); A. Baskurt, CNRS, Univ. de Lyon (France) and LIRIS, INSA-Lyon (France)

 Wavelet-based subsurface defect characterization in pulsed phase thermography for non-destructive evaluation [7248-13]
 G. Zauner, G. Mayr, G. Hendorfer, Upper Austria Univ. of Applied Sciences (Austria)

SESSION 5 PHYSICS-BASED MODELS AND APPLICATIONS II

- 7248 OF Image blur estimation based on the average cone of ratio in the wavelet domain [7248-15] L. Ilić, A. Pižurica, E. Vansteenkiste, W. Philips, Ghent Univ. (Belgium)
- 7248 0G New image quality measure based on wavelets [7248-16] E. Dumic, S. Grgic, M. Grgic, Univ. of Zagreb (Croatia)
- 7248 OH Power law scaling behavior of physiological time series in marathon races using wavelet leaders and detrended fluctuation analysis [7248-17] E. Wesfreid, CMLA, Ecole Normale Supérieure de Cachan (France) and LMPA, Univ. du Littoral (France); V. Billat, Unité INSERM 902, Génopole-Univ. d'Evry Val d'Essonne (France)

SESSION 6 IMAGE REPRESENTATION AND WATERMARKING

- From watermarking to in-band enrichment: future trends (Invited Paper) [7248-28] 7248 01 M. Mitrea, F. Prêteux, Institut TELECOM (France)
- 7248 OJ Locally adaptive complex wavelet-based demosaicing for color filter array images [7248-20] J. Aelterman, B. Goossens, A. Pižurica, W. Philips, Ghent Univ. (Belgium)

7248 OK Embedding distortion modeling for non-orthonormal wavelet based watermarking schemes [7248-21]

D. Bhowmik, C. Abhayaratne, The Univ. of Sheffield (United Kingdom)

- 7248 OL Image segmentation on cell-center sampled quadtree and octree grids [7248-22] B. Kim, NVIDIA (United States); P. Tsiotras, Georgia Institute of Technology (United States)
- 7248 OM A framework for evaluating wavelet based watermarking for scalable coded digital item adaptation attacks (Invited Paper) [7248-23] D. Bhowmik, C. Abhayaratne, The Univ. of Sheffield (United Kingdom)
- 7248 ON Multipurpose watermarking scheme using essentially non-oscillatory point-value decomposition [7248-18] G. Bhatnagar, Indian Institute of Technology Roorkee (India); S. Arrabolu, Univ. of Michigan (United States); R. Balasubramanian, Indian Institute of Technology Roorkee (India); K. Swaminathan, Indian Institute of Technology Madras (India)

Author Index

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Session Chairs

- 1 The JPEG 2000 Family of Standards Frederic Truchetet, Université de Bourgogne (France)
- Tools for Signal and Image Analysis
 Eva Wesfreid, Ecole Normale Supérieure de Cachan (France)

- 3 Compression Peter Schelkens, Vrije Universiteit Brussel (Belgium)
- Physics-Based Models and Applications I
 Atilla M. Baskurt, Université de Claude Bernard Lyon I (France)
- 5 Physics-Based Models and Applications II Atilla M. Baskurt, Université de Claude Bernard Lyon I (France)
- 6 Image Representation and Watermarking Gerald Zauner, FH OÖ Forschungs & Entwicklungs GmbH (Austria)